

INTERNATIONAL STANDARD



AMENDMENT 1

Information technology equipment – Safety – Part 1: General requirements



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IEC 60950-1

Edition 2.0 2009-12

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**Information technology equipment – Safety –
Part 1: General requirements**

INTERNATIONAL
ELECTROTECHNICAL
COMMISSION

PRICE CODE

W

ICS 35.020; 35.260

ISBN 2-8318-1068-7

FOREWORD

This amendment has been prepared by IEC technical committee 108: Safety of electronic equipment within the field of audio/video, information technology and communication technology.

The text of this amendment is based on the following documents:

FDIS	Report on voting
108/350/FDIS	108/357/RVD

Full information on the voting for the approval of this amendment can be found in the report on voting indicated in the above table.

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CONTENTS

Add the titles of the new annexes as follows:

Annex CC (normative), Evaluation of integrated circuit (IC) current limiters

Annex DD (normative), Requirements for the mounting means of rack-mounted equipment

Annex EE (normative), Household and home/office document/media shredders

Add the titles of the new figures as follows:

Figure 4C – Example for determining opening ‘X’ without a deflector

Figure 4H – Example for determining opening ‘X’ with a deflector

Figure EE.1 – Wedge probe (overall view)

Figure EE.2 – Wedge probe (tip details)